VLSI Design Flow

Problem statement:

If C=00, Take A as single-bit input serially and output into registers parallely C=01, Take B[0:3] input parallely and output into a register serially C=10, Take B[0:3] input parallely and output into registers parallely C=11, NOP

Assumptions and given:

- A is a single bit and B is 4-bit wide.
- The design has a synchronous clock and synchronous reset.
- The inputs and outputs should be registered.
- For C=00, we are considering 4 bit output so after 4 clock cycles 4 single bits from input will be parallely displayed in the output.

Specifications of the design:

- The design should have multiple functionalities serial in-parallel out, parallel in-serial out, parallel in-parallel out.
- These functionalities should be selected by a control signal named 'C' which is of 2 bits. The last operation/final operation is NOP(nothing happens when C=11).
- If C = 00, serial in-parallel out is selected in which A is taken as single bit input serially and X[0:3] is labeled and taken as output so it takes 4 clock cycles to get a 4 bit parallel output.
- C = 01, parallel in-serial out is selected
- Finally if C =10, parallel in-parallel out is selected which has a parallel input of B[0:3] and output is labeled and given by Z[0:3].
- The design should have a positive edge triggered clock and synchronous reset. So when the reset == 1 when the selected design's output should be 0.
- So in the above design A, B, C are inputs and X, Y, Z are outputs. These should be registered as in they should be passed through the registers. Apart the normal inputs there is 'loadinputs' which basically loads the inputs to reg so this should be set 1 in the test bench.
- The design used 90nm technology.
- Constraints are taken in three different variations which is given in synthesis.

Simulation and Coverage analysis:

Verilog code:

module SerialParallel(clk, rst,loadinputs,C, A, B, X, Y, Z); input clk,rst; input [1:0] C; input A; input loadinputs; //To load inputs to registers input [3:0] B;

```
reg [1:0] Creg; //Registers to which inputs are loaded
reg Areg;
               //Registers to which inputs are loaded
reg [3:0] Breg; //Registers to which inputs are loaded
output reg [3:0] X;
output reg [3:0] Z;
output reg Y;
//Syncronous clk and reset
always @(posedge clk)
begin
       if(rst) //checking if reset == 1
       begin
               X <= 4'b0000; //setting all the outputs to zeros
               Z \le 4'b0000;
               Y \le 1'b0;
       end
       if(loadinputs) //Loading inputs to registers.
       begin
               Breg [3:0] <= B [3:0];
               Creg[1:0] <= C[1:0];
               Areg \leq A;
       end
       case(Creg)
               2'b00:
                               begin
                                      X[0] \leq Areg;
                                      X[1] \le X[0];
                                      X[2] \le X[1];
                                      X[3] \le X[2];
                               end
               2'b01:
                               begin
                                      Y <= Breg[3];
                                      Breg[3] \le Breg[2];
                                      Breg[2] \leq Breg[1];
                                    Breg[1] <= Breg[0];
                              end
               2'b10:
                               begin
                                      Z[3] \le Breg[3];
                                      Z[2] \le Breg[2];
                                      Z[1] \le Breg[1];
```

```
Z[0] \mathrel{<=} \mathsf{Breg}[0]; end 2\mathsf{'b}11\mathsf{:} \; \mathsf{$display("No operation")$;} endcase end endmodule
```

Test benches 1:

```
module test_SP;
// Inputs
reg clk;
reg rst;
reg loadinputs;
reg [1:0] C;
reg A;
reg [3:0] B;
// Outputs
wire [3:0] X;
wire Y;
wire [3:0] Z;
// Instantiate the Design Under Test
SerialParallel uut (
        .clk(clk),
        .rst(rst),
        .loadinputs(loadinputs),
        .C(C),
        .A(A),
        .B(B),
        .X(X),
        .Y(Y),
        Z(Z)
);
initial begin
        // Initialize Inputs
        clk = 0;
        rst = 0;
        loadinputs = 1;
        C = 0;
        A = 0;
        B = 0;
        #100;
```

```
end
       initial
       begin
               C = 00;
               #80 C = 01;
               B = 4'b1100;
               #80 C = 10;
               B = 4'b1010;
               #50 C = 11;
               #50 \text{ rst} = 1;
       end
       always #20 A = \simA;
       always #10 clk = \simclk;
       initial
       #1000 $finish;
endmodule
```

Test benches 2:

```
module test_SP;
// Inputs
reg clk;
reg rst;
reg loadinputs;
reg [1:0] C;
reg A;
reg [3:0] B;
// Outputs
wire [3:0] X;
wire Y;
wire [3:0] Z;
// Instantiate the Unit Under Test (UUT)
SerialParallel uut (
        .clk(clk),
        .rst(rst),
       .loadinputs(loadinputs),
        .C(C),
        .A(A),
        .B(B),
```

```
.X(X),
               .Y(Y),
               .Z(Z)
       );
       initial begin
               // Initialize Inputs
               clk = 0;
               rst = 0;
               loadinputs = 1;
               C = 0;
               A = 1;
               B = 0;
               // Wait 100 ns for global reset to finish
               #100;
               // Add stimulus here
       end
       initial
       begin
               C = 00;
               #80 C = 01;
               B = 4'b1001;
               #80 C = 10;
               B = 4'b1110;
               #50 rst = 1;
       end
       always #20 A = \simA;
       always #10 clk = \simclk;
       initial
       #1000 $finish;
endmodule
```

Test benches 3:

```
module test_SP;
// Inputs
reg clk;
reg rst;
reg loadinputs;
reg [1:0] C;
reg A;
reg [3:0] B;

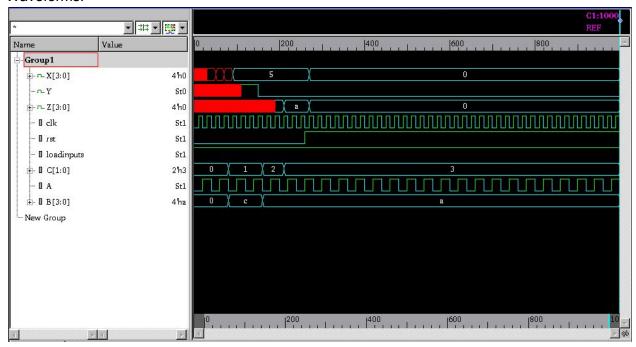
// Outputs
wire [3:0] X;
```

```
wire Y;
        wire [3:0] Z;
        // Instantiate the Design Under Test
        SerialParallel uut (
                .clk(clk),
                .rst(rst),
               .loadinputs(loadinputs),
                .C(C),
               .A(A),
               .B(B),
               .X(X),
               .Y(Y),
                Z(Z)
        );
        initial begin
               // Initialize Inputs
               clk = 0;
               rst = 0;
               loadinputs = 1;
               C = 0;
               A = 0;
               B = 0;
               #100;
        end
        initial
        begin
               C = 00;
               #80 C = 01;
               B = 4'b0111;
               #80 C = 10;
               B = 4'b1011;
        end
        always #20 A = \simA;
        always #10 clk = \simclk;
        initial
        #1000 $finish;
endmodule
```

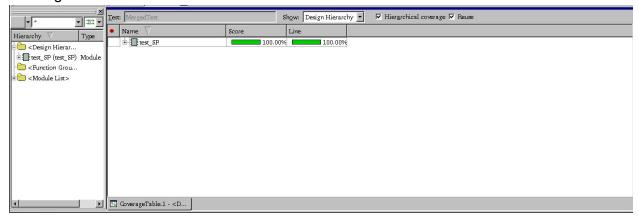
Simulation Results and analysis: I used VCS for simulation of my design which is a Synopsis tools for the above three test benches. The results of the above test benches are as follows:

Test bench 1: In this test bench, we had A toggling from 0 to 1 at a frequency of 20ns and a clock which is operating at 10ns. Initially, C = 00 for 80ns i.e 4 clock cycles(to transfer 4 bits to output). Hence after 4 cycles 0101 should be in the output and later on after rst ==1 it should be 0. We can see 5 i.e 0101 and 0 when rst == 1 in the A waveform. Similarly for next 80ns C = 01 for parallel input to serial output which takes 4 clock cycles. For this interval B = 4'1100 hence the Y waveform is 1100 and later on after rst Y = 0. C = 10 takes only one clock cycles to transfer the bits. Since B = 4'b1010 it got directly reflected into Z waveform and it is 0 when rst ==1. The last case does nothing. And this test bench has 100% code coverage since it covers all the case statements 00 to 11 with rst == 0 and 1 at different intervals of clock(In a way it covers all the RTL statements in the code).

Waveforms:

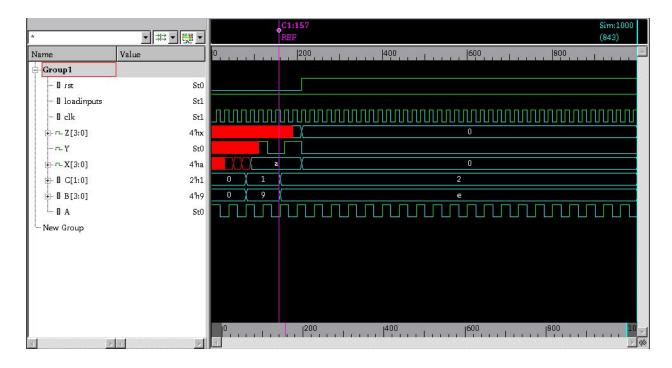


Coverage:

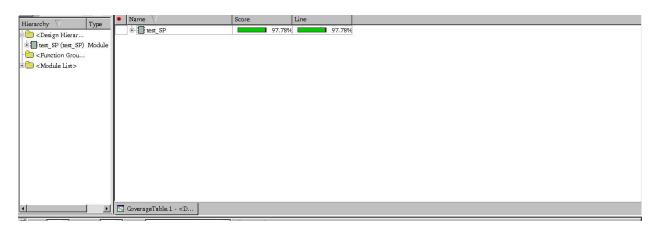


Test bench 2: This test bench has few changes. The data the is being transferred it different in this case. For case C=01 and 10, values of B are 1001, 1110 respectively. And the values of A in initialize as 1 so 1010 is reflected in X rather than 0101. It doesn't cover the last case so it got only 97.7 coverage.

Waveforms:

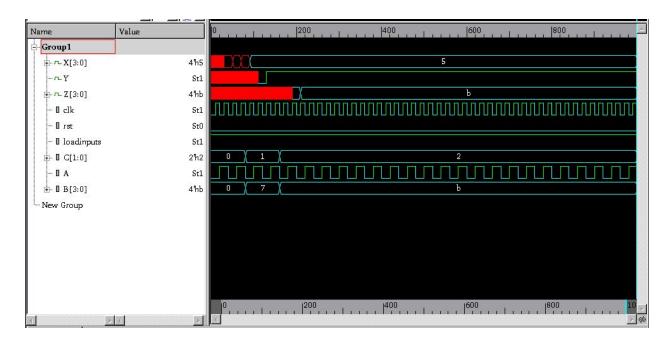


Coverage:

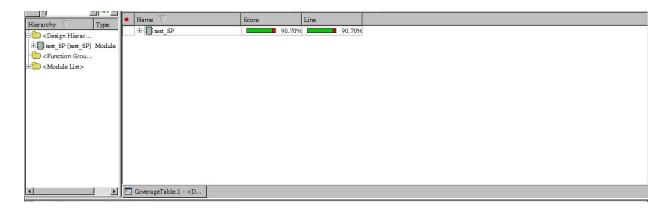


Test Bench 3: Similar to test bench 2, there are minor changes like different inputs for C = 01 and 10. The rst is not applied here. It has a code coverage of 90.7%

Waveforms:



Coverage:



Commands used for VCS:

For simulation: vcs -v -R test_SP.v SerialParallel.v -full64 -debug_all

./simv -gui

For coverage: vcs -v -R test_SP.v SerialParallel.v -full64 -cm line

./simv -cm line

dve -covdir simv.vdb/ -full64

Synthesis: I used Design compiler for Synthesis of the design. DC is a Synopsis tool. It uses 90nm technology as it's set up. First, area is minimized making timing constraints relaxed. All the results are compared between the area, slack and the power.

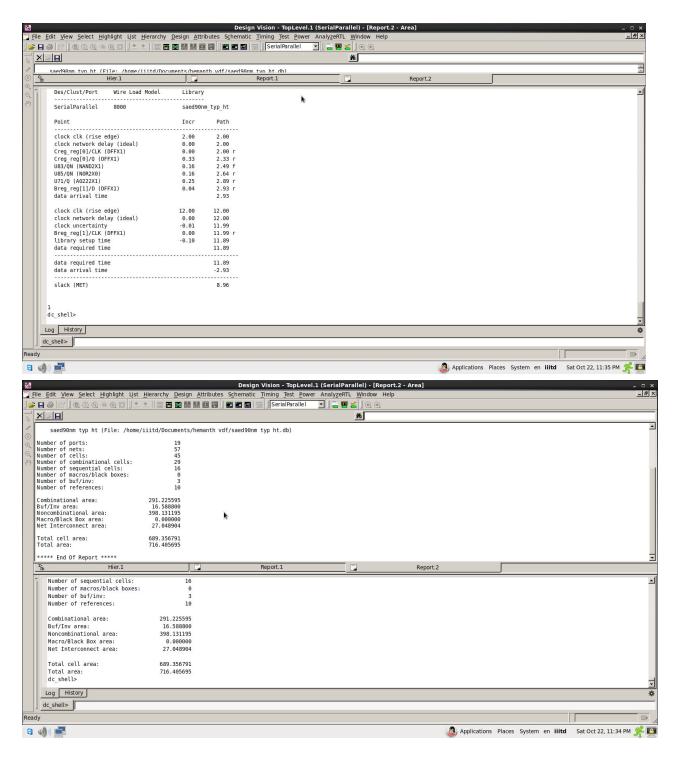
Constraints 1:

Minimum Area

Created by write_sdc on Sat Oct 21 23:47:06 2016

set_units -time ns -resistance MOhm -capacitance fF -voltage V -current uA set_max_area 717 set_max_fanout 10 [current_design] create_clock [get_ports clk] -period 10 -waveform {2 3} set_clock_transition -max -rise 0.1 [get_clocks clk] set_clock_transition -max -fall 0.1 [get_clocks clk] set_clock_transition -min -rise 0.1 [get_clocks clk] set_clock_transition -min -fall 0.1 [get_clocks clk] set_clock_transition -min -fall 0.1 [get_ports clk] set_input_delay -clock clk -max 0.01 [get_ports Y]

set clock uncertainty 0.01 [get ports clk] Design Vision - TopLevel.1 (SerialParallel) _____File _Edit _View _Select _Highlight List _Hierarchy Schematic Timing Test Power 📤 || 🔤 🚟 👪 👪 🔯 😰 📗 🎆 🗃 😭 || Serial Parallel T | = = < | | @ × 46 Cell Internal Power = 5.7819 uW Net Switching Power = 766.3432 nW = 6.5483 uW Total Dynamic Power Cell Leakage Power = 11.2099 uW Leakage Power Switching Power Power Group Attrs io pad memory black box clock network register sequential combinational 0.0000 0.0000 0.0000 0.0000 11.8731 0.00%) 0.00%) 0.00%) 0.00%) 66.86%) 0.0000 0.0000 0.0000 4.4401 0.0000 1.3418 0.0000 0.5649 0.0000 3.9783e+06 0.0000 5.8850 0.00%) 1.1210e+07 pW Total 5.7819 uW 0.7663 uW 17.7581 uW ***** End Of Report ***** °€ Hier.1 Report.1 Report.2 Power Group Power Power Power io_pad 0.0000 0.0000 0.0000 0.0000 0.00%) 0.0000 0.0000 0.0000 0.0000 black_box clock_network 0.0000 0.0000 0.0000 0.0000 0.00%) register 4.4401 0.2014 7.2316e+06 11.8731 66.86%) sequential 0.0000 combinational 3.9783e+06 33.14%) 1.3418 0.5649 5.8850 5.7819 uW 0.7663 uW 1.1210e+07 pW 17.7581 uW dc shell> Log History dc_shell> Ready



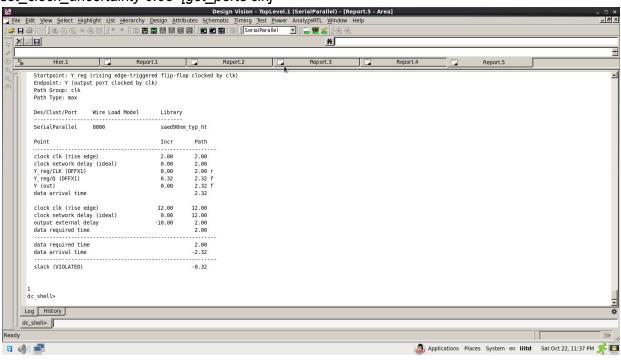
The above results are when the timing constraints are relaxed so the total area that is coming out to be is approx 716. As the timing constraints are relaxed, kept the values normal. The slack is positive and around 9. And the power is 17.5uW. The netlist is saved as 'netlist1.v'.

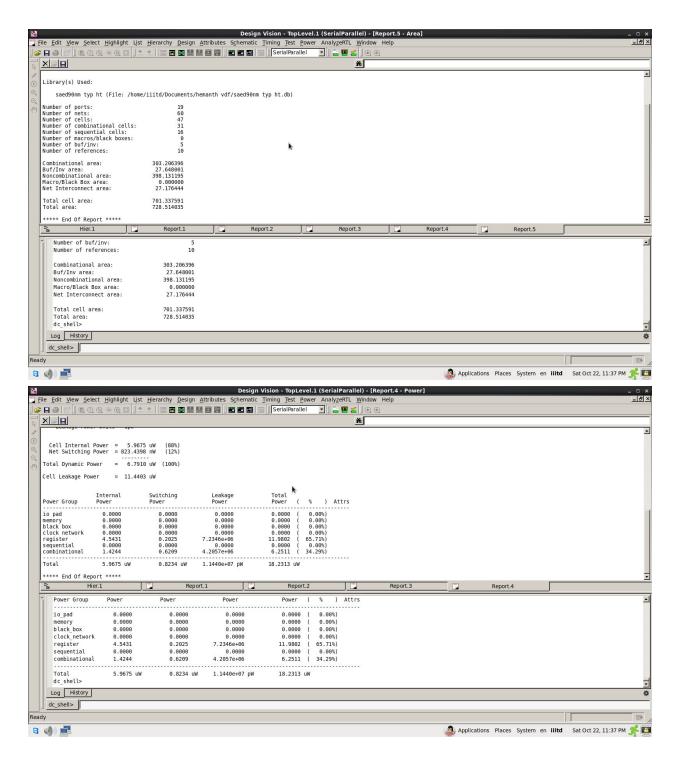
Constraints 2:

Best timing

Created by write sdc on Fri Oct 21 17:26:38 2016

set_units -time ns -resistance MOhm -capacitance fF -voltage V -current uA set_max_fanout 10 [current_design] create_clock [get_ports clk] -period 10 -waveform {2 3} set_clock_transition -max -rise 0.2 [get_clocks clk] set_clock_transition -min -rise 0.2 [get_clocks clk] set_clock_transition -max -fall 0.3 [get_clocks clk] set_clock_transition -min -fall 0.3 [get_clocks clk] set_input_delay -clock clk -max 6 [get_ports rst] set_output_delay -clock clk -max 10 [get_ports Y] set_clock_uncertainty 0.03 [get_ports clk]





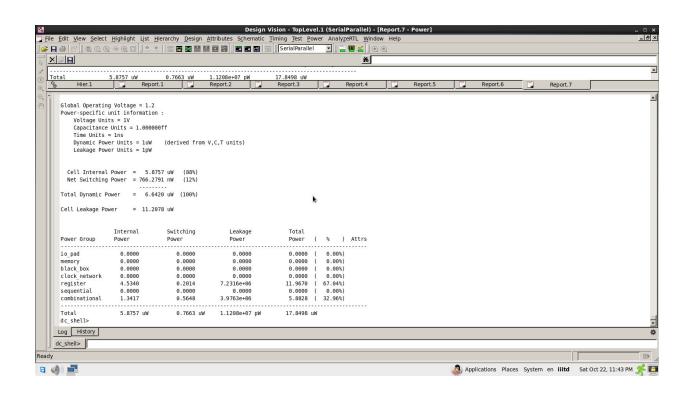
The slack is -0.32 which is calculated by required time - arrival time. As given in the question, the timing constraints are kept in such a way that the slack is negative and for this constraints the area that is coming out to be approx 728 with a power of 18.2uW. The netlist is saved as 'netlist2.v'

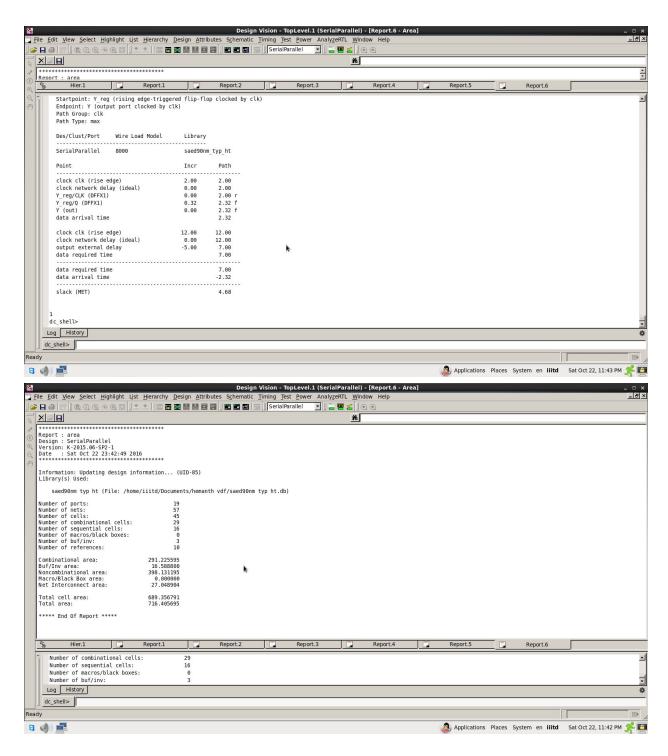
Constraints 3:

Area and timing:

Created by write_sdc on Fri Oct 21 17:27:49 2016

set_units -time ns -resistance MOhm -capacitance fF -voltage V -current uA set_max_area -ignore_tns 717
set_max_fanout 10 [current_design]
create_clock [get_ports clk] -period 10 -waveform {2 3}
set_clock_transition -max -rise 0.2 [get_clocks clk]
set_clock_transition -min -rise 0.2 [get_clocks clk]
set_clock_transition -max -fall 0.3 [get_clocks clk]
set_clock_transition -min -fall 0.3 [get_clocks clk]
set_input_delay -clock clk -max 6 [get_ports rst]
set_output_delay -clock clk -max 10 [get_ports Y]
set_clock_uncertainty 0.03 [get_ports clk]



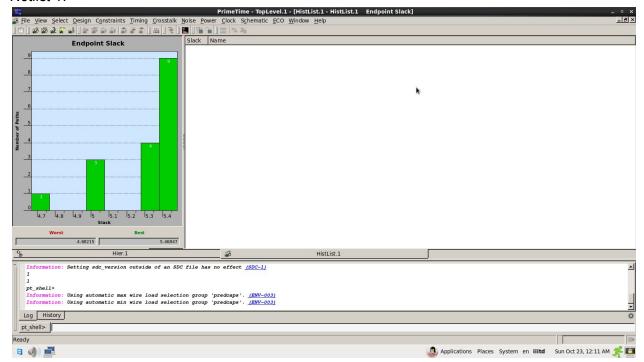


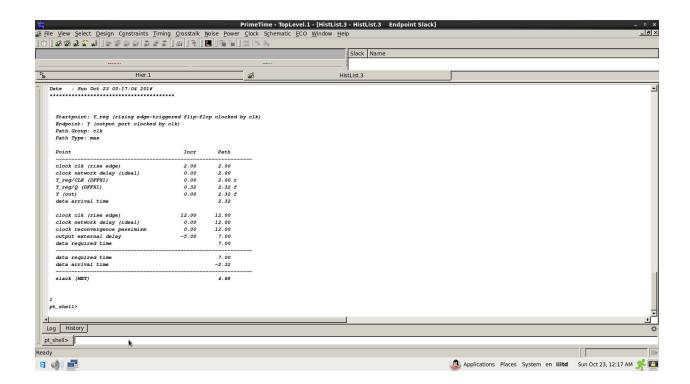
Last constraint deals with positive slack which not too high as constraint 1 and has a area optimization using set_max_area. As we can see the area is optimized from the previous design where didn't try to limit area. This time we tried to optimize the area keeping the using area optimization by disabling total negative slack. Hence the area of the design is a bit optimized as we can see. The netlist is saved as 'netlist3.v'.

Commands used for Synthesis: dc_shell start_gui

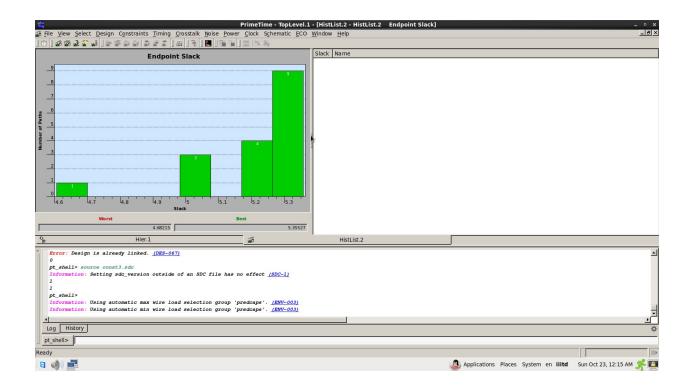
STA: I am using PrimeTime for STA. Static timing analysis for performed for all the netlists that are generated in the synthesis.

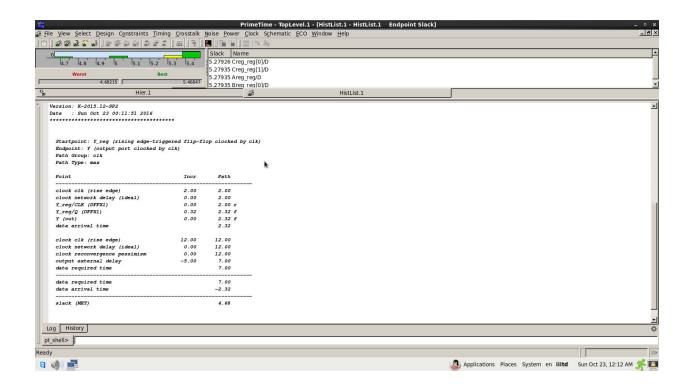
Netlist 1:



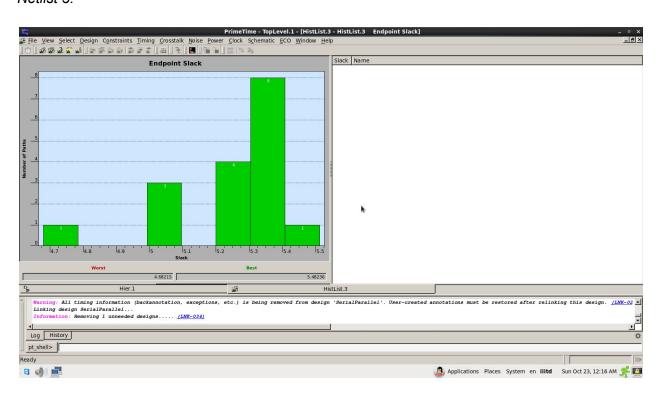


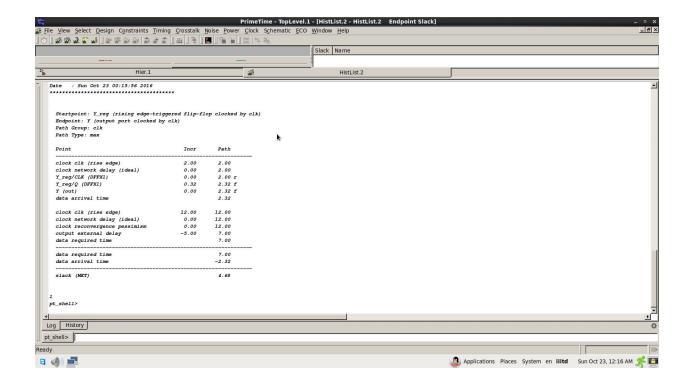
Netlist 2:





Netlist 3:





Analysis: report_timing gives the worst slack by default since same constraint file used for all the netlist the worst slack is same for all which is coming out to be 4.68. We can also see the startpoint and endpoint of the worst case slack in the timing report. In case of a negative slack we can inspect the path and schematic try to add a buffer or something to fix it. Since the netlist are different the best slack and the remaining paths has different slacks. The constraints used are initially to set the link to library ad read the netlist. Later on we need to link the library files to netlist and source the constraint file and start gui.

Commands used for PrimeTime: set link_library {* path}

read_verilog netlist.v

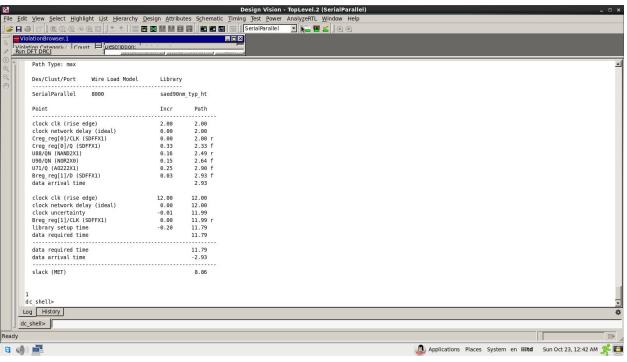
link

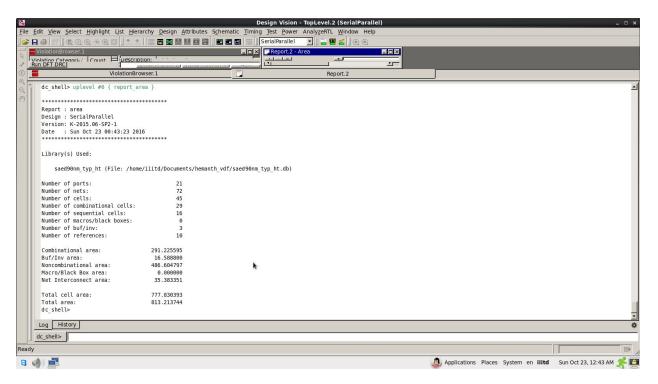
source constraints.sdc

start_gui

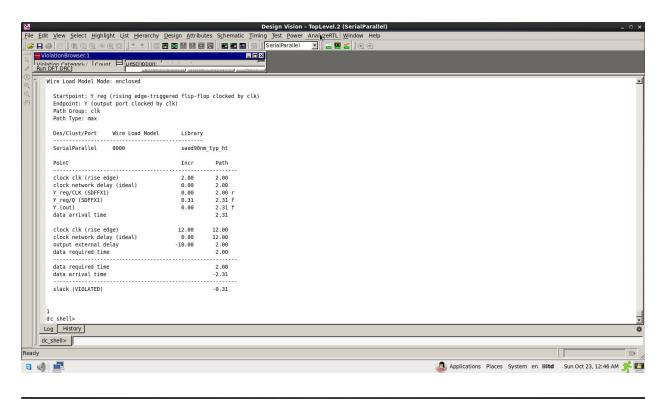
DFT: The tool used to perform DFT is Design Compiler. I performed DFT for all the constraints that were created in step 3. Area and timing of the previous and new netlist is compared.

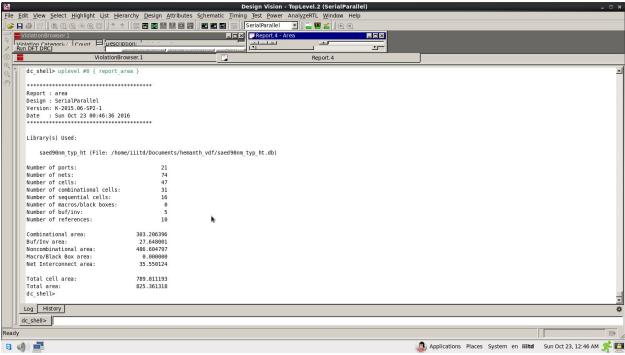
Constraints 1:



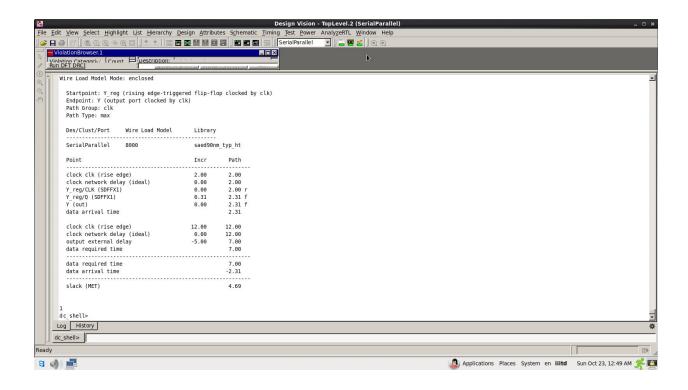


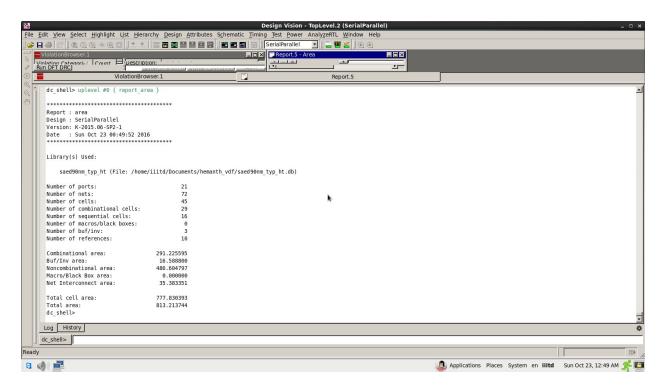
Constraints 2:





Constraints 3:





Analysis: As we can see the slack of the design is earlier almost the same or a bit optimize. Of course the area of the design should be increased to some extent because we are introducing scan flipflops into the design which increases the area. This is applied to all the design comparison above from constraint 1 to constraint 3.

```
Commands used for DFT:
set_scan_configuration -style multiplexed_flip_flop
compile -scan
set_dft_signal -view existing_dft -type ScanClock -port clk -timing [list 40 60]
create_test_protocol
dft_drc
set_scan_configuration -chain_count 1
preview_dft
insert_dft
```